Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/536,956	SHIN ET AL.
Examiner	Art Unit

Teresa J. Walberg

3753

	SEARCHED					
Class	Subclass	Date	Examiner			
165	164, 166	4/14/2006	TJW			
Above	UPDATED	9/6/2006	TJW			
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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(INCLUDING SEARCH STRATEGY)		
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